Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/510,704	HATANAKA ET AL.		
Examiner	Art Unit		
John S. Chu	1752		

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SEARCHED					
Class	Subclass	Date	Examiner		
430	191	10/2005	Sic-		
430	192	1	1		
430	193				
430	165				
430	280.1				
430	326				

INTERFERENCE SEARCHED						
Class	Subclass	Date		Examiner		
430	190,191	10/200	15	je	ر	
430	192	1			1	
430	193					
430/28	0.1,326					

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